

## 1. Description

The KIA40N06B is the highest performance trench N-ch MOSFETs with extreme high cell density, which provide excellent  $R_{DS(on)}$  and gate charge for most of the synchronous buck converter applications. The KIA40N06B meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

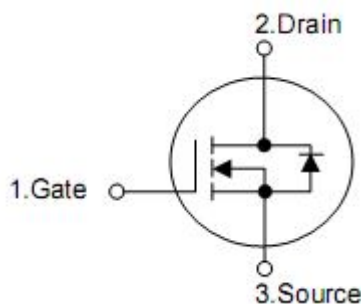
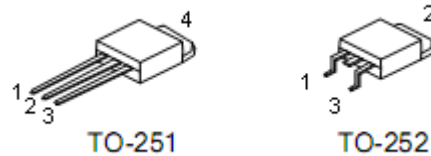
## 2. Features

- $R_{DS(on)}=18m\Omega @ V_{DS}=60V$
- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent  $C_{dv/dt}$  effect decline
- 100% EAS Guaranteed
- Green Device Available

## 3. Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- LCD/LED back light

## 4. Symbol



Pin	Function
1	Gate
2	Drain
3	Source

## 5. Absolute maximum ratings

Parameter	Symbol	Rating	Units	
Drain-source voltage	$V_{DS}$	60	V	
Gate-source voltage	$V_{GS}$	+20	V	
Continuous drain current, $V_{GS}@10V^1$	$I_D$	$T_C=25^\circ C$	38	A
		$T_C=100^\circ C$	30	A
Pulsed drain current <sup>2</sup>	$I_{DM}$	80	A	
Single pulse avalanche energy <sup>3</sup>	$E_{AS}$	67	mJ	
Avalanche current	$I_{AS}$	28	A	
Total power dissipation <sup>4</sup>	$P_D$	45	W	
$T_C=25^\circ C$				
Operation junction temperature range	$T_J$	-55 to 150	$^\circ C$	
Storage temperature range	$T_{STG}$	-55 to 150	$^\circ C$	

## 6. Thermal characteristics

Parameter	Symbol	Typ	Max	Unit
Thermal resistance, Junction-ambient <sup>1</sup>	$R_{\theta JA}$	--	62	$^\circ C/W$
Thermal resistance, Junction-case <sup>1</sup>	$R_{\theta JC}$	--	2.8	

## 7. Electrical characteristics

( $T_J=25^{\circ}\text{C}$ , unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-source breakdown voltage	$BV_{DSS}$	$V_{GS}=0V, I_D=250\mu A$	60	-	-	V
$BV_{DSS}$ temperature coefficient	$\Delta BV_{DSS}/\Delta T_J$	Reference to $25^{\circ}\text{C}$ , $I_D=1mA$		0.057		$V/^{\circ}\text{C}$
Static drain-source on-resistance <sup>2</sup>	$R_{DS(on)}$	$V_{GS}=10V, I_D=15A$		14	18	m $\Omega$
		$V_{GS}=4.5V, I_D=10A$		16	20	
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.2		2.5	V
$V_{GS(th)}$ temperature coefficient	$\Delta V_{GS(th)}$			-5.68		$mV/^{\circ}\text{C}$
Drain-source leakage current	$I_{DSS}$	$V_{DS}=48V, V_{GS}=0V$ $T_J=25^{\circ}\text{C}$			1	$\mu A$
		$V_{DS}=48V, V_{GS}=0V$ $T_J=55^{\circ}\text{C}$			5	$\mu A$
Gate- source leakage current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$			$\pm 100$	nA
Forward transconductance	$g_{fs}$	$V_{DS}=5V, I_D=15A$		45		S
Gate resistance	$R_g$	$V_{DS}=0V, V_{GS}=0V, f=1MHz$		1.7	3.4	$\Omega$
Total gate charge(4.5V)	$Q_g$	$V_{DS}=48V, V_{GS}=4.5V$ $I_D=12A$	-	17.6		nC
Gate-source charge	$Q_{gs}$			5.35		
Gate-drain charge	$Q_{gd}$			6.81		
Turn-on delay time	$t_{d(on)}$	$V_{DD}=15V, I_D=1A,$ $R_G=3.3\Omega, V_{GS}=10V$		15.5		ns
Rise time	$t_r$			2.2		
Turn-off delay time	$t_{d(off)}$			72.8		
Fall time	$t_f$			3.8		
Input capacitance	$C_{iss}$	$V_{DS}=15V, V_{GS}=0V,$ $f=1MHz$		2423		pF
Output capacitance	$C_{oss}$			145		
Reverse transfer capacitance	$C_{rss}$			97		
Single pulse avalanche energy <sup>5</sup>	EAS	$V_{DD}=25V, L=0.1mH,$ $I_{AS}=15A$	19			mJ
Continuous source current <sup>1,6</sup>	$I_S$	$V_G=V_D=0V,$ Force current			38	A
Pulsed source current <sup>2,6</sup>	$I_{SM}$				80	A
Diode forward voltage <sup>2</sup>	$V_{SD}$	$V_{GS}=0V, I_S=1A, T_J=25^{\circ}\text{C}$			1	V

Note:1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 20Z copper.

2.The data tested by pulsed, pulse width $\leq 300\mu s$ , duty cycle $\leq 2\%$

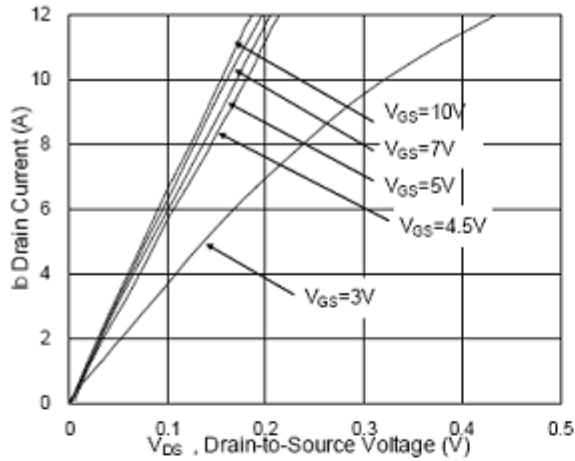
3.The EAS data shows Max.rating.The test condition is  $V_{DD}=25V, V_{GS}=10V, L=0.1mH, I_{AS}=28A$

4.The power dissipation is limited by  $150^{\circ}\text{C}$  junction temperature

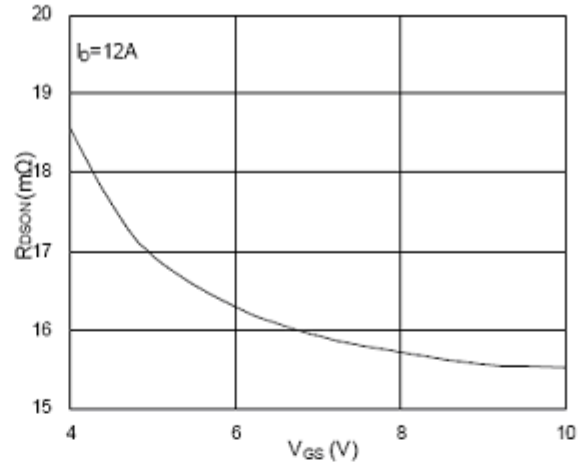
5.The Min, value is 100% EAS tested guarantee.

6.The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.

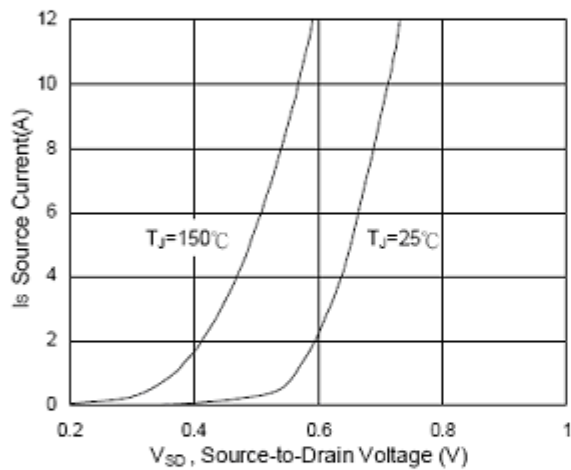
**8. Test circuits and waveforms**



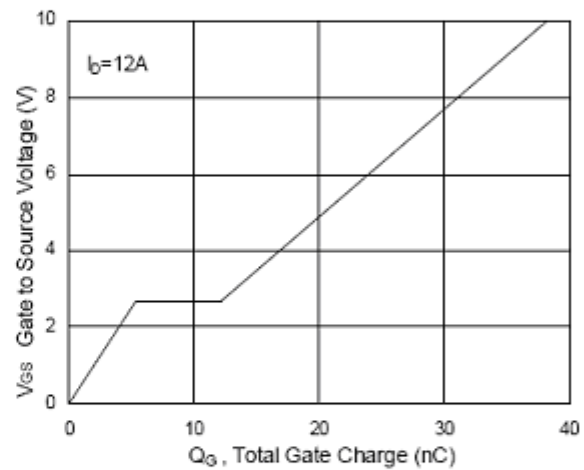
**Fig.1 Typical Output Characteristics**



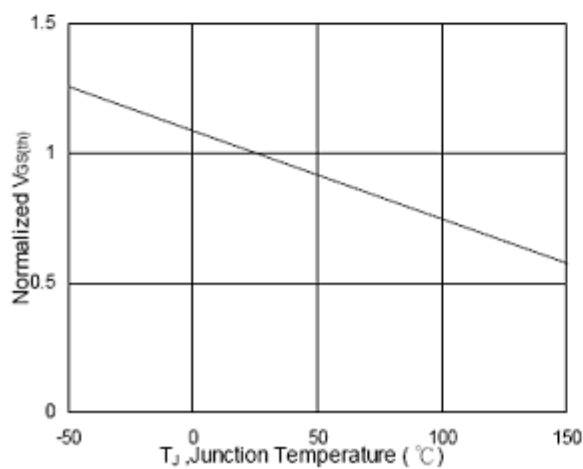
**Fig.2 On-Resistance v.s Gate-Source.**



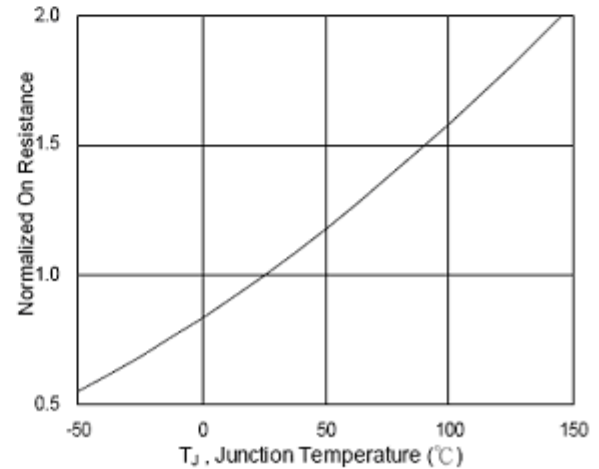
**Fig.3 Forward Characteristics of Reverse**



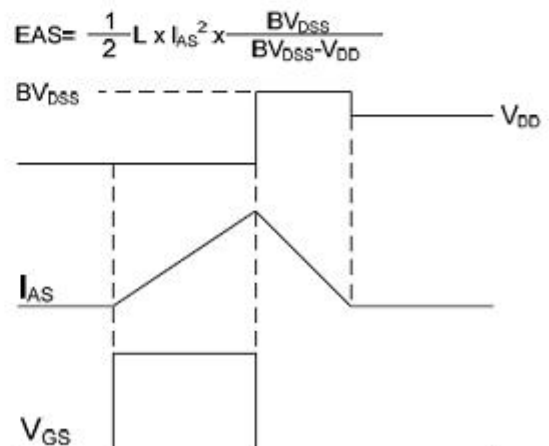
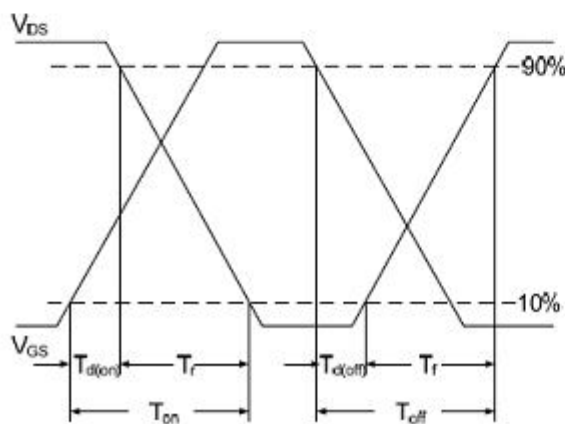
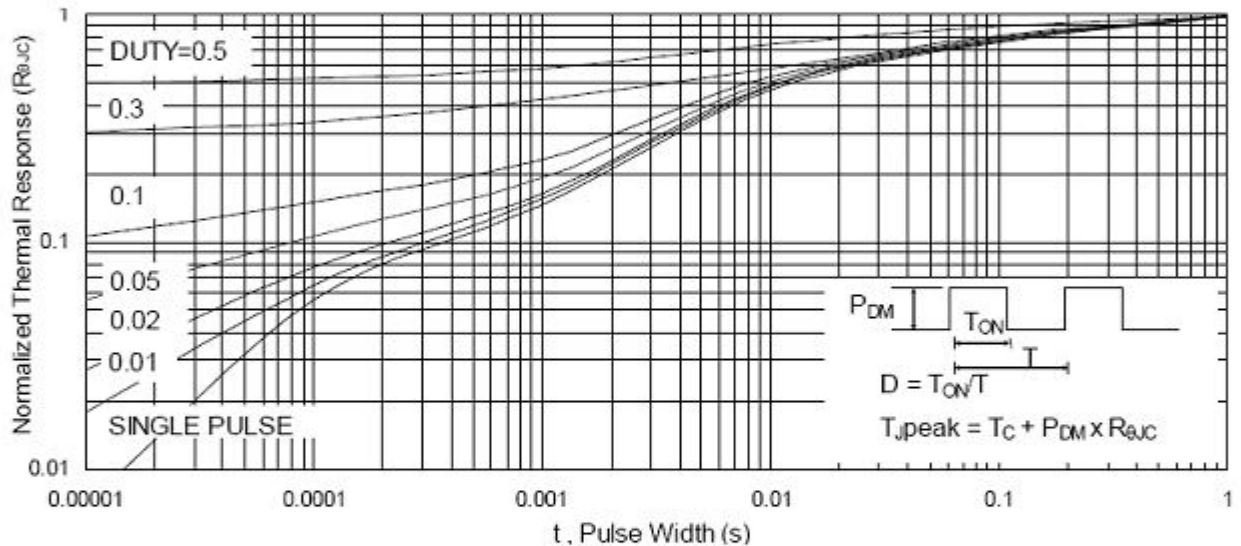
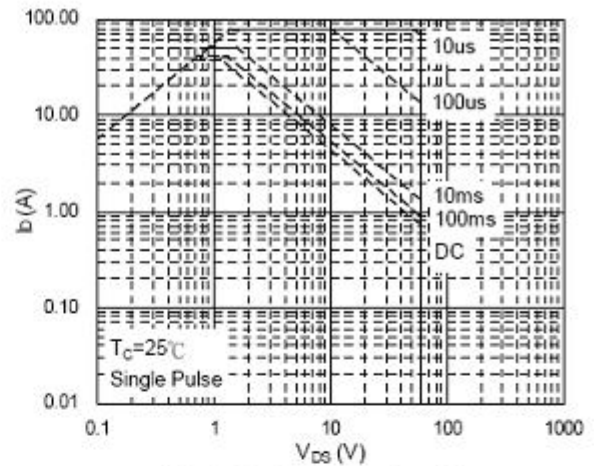
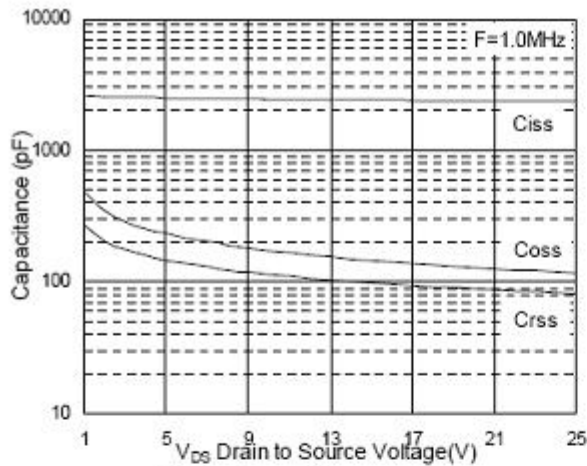
**Fig.4 Gate-Charge characteristics**



**Fig.5 Normalized V<sub>GS(th)</sub> v.s T<sub>J</sub>**



**Fig.6 Normalized R<sub>DS(on)</sub> v.s T<sub>J</sub>**



$$EAS = \frac{1}{2} L \times I_{AS}^2 \times \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$